# Product Preview

# **Power MOSFET**

# 20 V, 75 A, Single N-Channel, μ8FL

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

# **Applications**

- DC-DC Converters
- Power Load Switch
- Notebook Battery Management

# MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise stated)

Param	Symbol	Value	Unit		
Drain-to-Source Voltage	$V_{DSS}$	20	V		
Gate-to-Source Voltage	$V_{GS}$	±20	V		
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	19.4	Α
Current R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 85°C		14.5	
Power Dissipation $R_{\theta JA}$ (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	2.16	W
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	28	Α
Current $R_{\theta JA} \le 10 \text{ s}$ (Note 1)		T <sub>A</sub> = 85°C		21	
Power Dissipation $R_{\theta JA} \le 10 \text{ s (Note 1)}$	Steady	T <sub>A</sub> = 25°C	P <sub>D</sub>	4.5	W
Continuous Drain	State	T <sub>A</sub> = 25°C	I <sub>D</sub>	12.0	Α
Current R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 85°C		8.9	
Power Dissipation R <sub>0JA</sub> (Note 2)		T <sub>A</sub> = 25°C	P <sub>D</sub>	0.82	W
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	75	Α
Current R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 85°C		56	
Power Dissipation $R_{\theta JC}$ (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	33	W
Pulsed Drain Current	$T_A = 25^{\circ}$	C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	174	Α
Operating Junction and S	T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C		
Source Current (Body Die	IS	30	Α		
Drain to Source dV/dt	dV/dt	6.0	V/ns		
Single Pulse Drain-to-So $(T_J = 25^{\circ}C, V_{DD} = 50 \text{ V}, V_{DD} = 0.1 \text{ mH}, R_G = 25 \Omega)$	E <sub>AS</sub>	84	mJ		
Lead Temperature for So (1/8" from case for 10 s)	TL	260	°C		

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- Surface-mounted on FR4 board using the minimum recommended pad size.
- This is the absolute maximum ratings. Parts are 100% tested at  $T_J = 25^{\circ}$ C,  $V_{GS} = 10 \text{ V}, I_L = 29 \text{ A}, E_{AS} = 42 \text{ mJ}.$

This document contains information on a product under development. ON Semiconductor reserves the right to change or discontinue this product without notice.

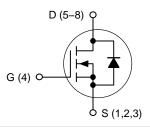


# ON Semiconductor®

#### www.onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> MAX	I <sub>D</sub> MAX
20 V	3.6 mΩ @ 10 V	75 A
	5.1 mΩ @ 4.5 V	738

# **N-Channel MOSFET**





# (µ8FL) **CASE 511AB**

#### **MARKING DIAGRAM**



5N02 = Specific Device Code = Assembly Location Α

= Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

# ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>		
NTTFS005N02CTAG	WDFN8 (Pb-Free)	1500 / Tape & Reel		

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

# THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	3.8	
Junction-to-Ambient - Steady State (Note 4)	$R_{ heta JA}$	57.8	°C/W
Junction-to-Ambient - Steady State (Note 5)	$R_{ heta JA}$	151.9	*C/vv
Junction-to-Ambient - (t ≤ 10 s) (Note 4)	$R_{ heta JA}$	27.6	

 Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.
 Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS				-			
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		20			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				11.7		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 \text{ V}, \qquad T_{J} = 25^{\circ}\text{C}$				1.0	
		$V_{DS} = 16 \text{ V}$	T <sub>J</sub> = 125°C			10	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub>	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 6)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= 250 μΑ	1.3		2.2	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.0		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 30 A		2.9	3.6	0
		V <sub>GS</sub> = 4.5 V	V <sub>GS</sub> = 4.5 V I <sub>D</sub> = 30 A		4.1	5.1	mΩ
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>I</sub>	<sub>O</sub> = 15 A		68		S
Gate Resistance	$R_{G}$	T <sub>A</sub> = 25°C			1.0		Ω
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>ISS</sub>				1988		
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 15 V			1224		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				71		1
Capacitance Ratio	C <sub>RSS</sub> /C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 15	5 V, f = 1 MHz		0.036		
Total Gate Charge	Q <sub>G(TOT)</sub>				14.5		
Threshold Gate Charge	Q <sub>G(TH)</sub>				2.9		]
Gate-to-Source Charge	$Q_{GS}$	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			5.2		nC
Gate-to-Drain Charge	$Q_{GD}$				5.5		
Gate Plateau Voltage	$V_{GP}$			3.1		V	
Total Gate Charge	$Q_{G(TOT)}$	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 1		31		nC	
SWITCHING CHARACTERISTICS (Note 7)							
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 15 \text{ A}, R_{G} = 3.0 \Omega$			11		
Rise Time	t <sub>r</sub>				30		ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>				20		
Fall Time	t <sub>f</sub>				8.0		

<sup>6.</sup> Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .
7. Switching characteristics are independent of operating junction temperatures.

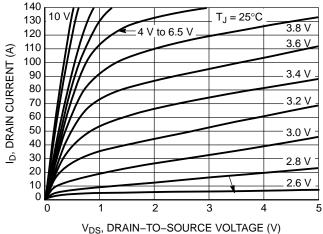
# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 7)			•	•	•	
Turn-On Delay Time	t <sub>d(ON)</sub>			8.0		- ns	
Rise Time	t <sub>r</sub>	$V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 15 \text{ A}, R_{G} = 3.0 \Omega$			25		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				26		
Fall Time	t <sub>f</sub>				5.0		
DRAIN-SOURCE DIODE CHARACT	ERISTICS				•	•	-
Forward Diode Voltage	$V_{SD}$	$V_{CS} = 0 \text{ V}.$ $T_J = 25^{\circ}\text{C}$			0.77	1.1	.,
		$V_{SD}$ $V_{GS} = 0 \text{ V},$ $I_{S} = 10 \text{ A}$ $T_{J} = 125$	T <sub>J</sub> = 125°C		0.62		
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$			42.4		
Charge Time	t <sub>a</sub>				21.1		ns
Discharge Time	t <sub>b</sub>				21.3		
Reverse Recovery Charge	$Q_{RR}$				34.4		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

<sup>6.</sup> Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
7. Switching characteristics are independent of operating junction temperatures.

# **TYPICAL CHARACTERISTICS**



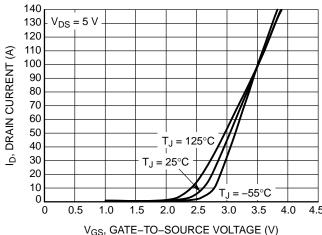
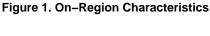


Figure 2. Transfer Characteristics



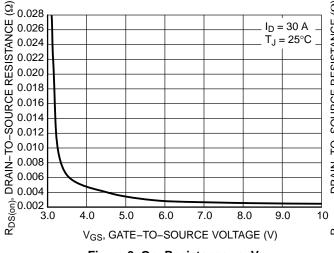


Figure 3. On-Resistance vs. V<sub>GS</sub>

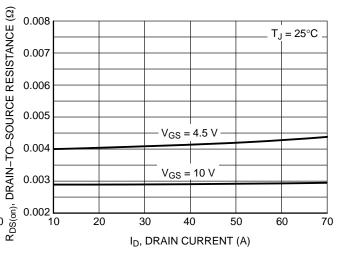


Figure 4. On-Resistance vs. Drain Current and **Gate Voltage** 

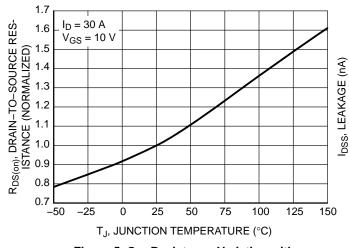


Figure 5. On-Resistance Variation with **Temperature** 

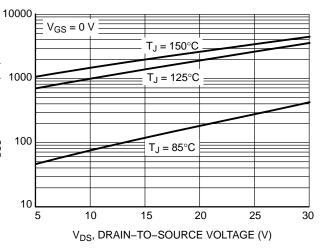


Figure 6. Drain-to-Source Leakage Current vs. Voltage

### **TYPICAL CHARACTERISTICS**

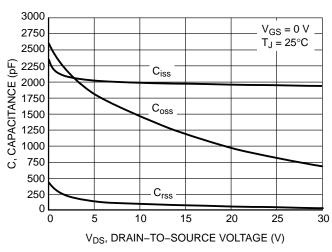


Figure 7. Capacitance Variation

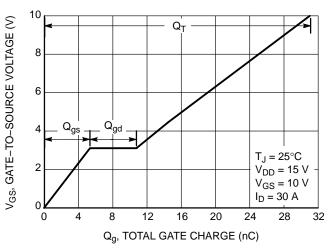


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

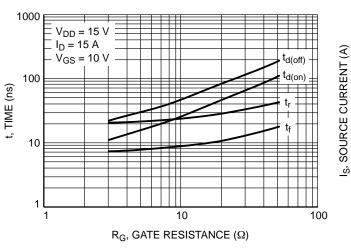


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

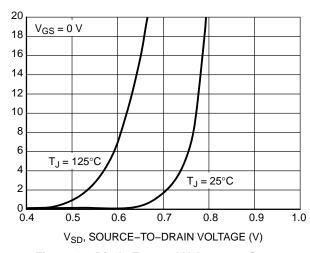


Figure 10. Diode Forward Voltage vs. Current

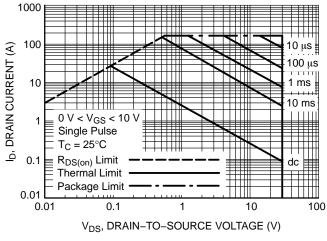


Figure 11. Maximum Rated Forward Biased Safe Operating Area

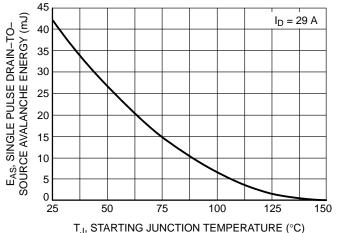


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

# **TYPICAL CHARACTERISTICS**

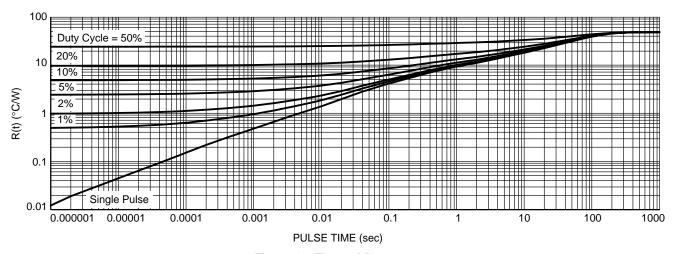


Figure 13. Thermal Response

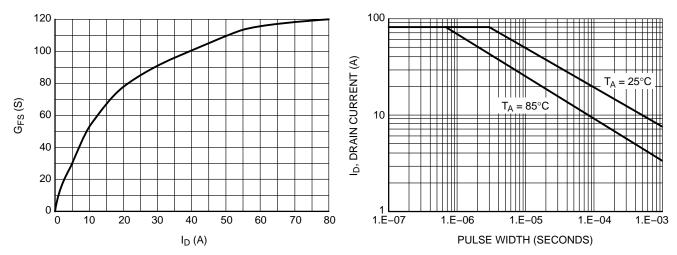
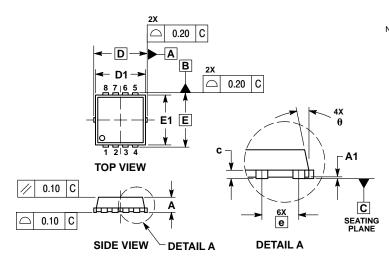


Figure 14. G<sub>FS</sub> vs. I<sub>D</sub>

Figure 15. Avalanche Characteristics

#### PACKAGE DIMENSIONS

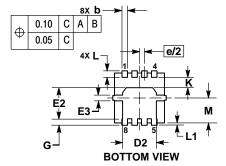
# WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D



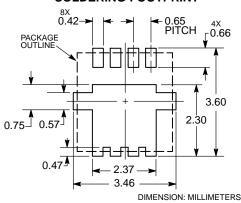
#### NOTES

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
   CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.70	0.75	0.80	0.028	0.030	0.031	
A1	0.00		0.05	0.000		0.002	
b	0.23	0.30	0.40	0.009	0.012	0.016	
С	0.15	0.20	0.25	0.006	0.008	0.010	
D	;	3.30 BSC			0.130 BSC		
D1	2.95	3.05	3.15	0.116	0.120	0.124	
D2	1.98	2.11	2.24	0.078	0.083	0.088	
E		3.30 BSC		0.130 BSC			
E1	2.95	3.05	3.15	0.116	0.120	0.124	
E2	1.47	1.60	1.73	0.058	0.063	0.068	
E3	0.23	0.30	0.40	0.009	0.012	0.016	
е	0.65 BSC			(	0.026 BS0	3	
G	0.30	0.41	0.51	0.012	0.016	0.020	
K	0.65	0.80	0.95	0.026	0.032	0.037	
L	0.30	0.43	0.56	0.012	0.017	0.022	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
M	1.40	1.50	1.60	0.055	0.059	0.063	
θ	0 °		12 °	0 °		12 °	



# **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

ON Semiconductor and III) are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <a href="https://www.onsemi.com/site/pdf/Patent-Marking.pdf">www.onsemi.com/site/pdf/Patent-Marking.pdf</a>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages.

Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that ON Semiconductor was negligent regarding the design or manufacture of the part. ON Semiconductor is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

# PUBLICATION ORDERING INFORMATION

#### LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free USA/Canada

Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910 Japan Customer Focus Center

Phone: 81–3–5817–1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative